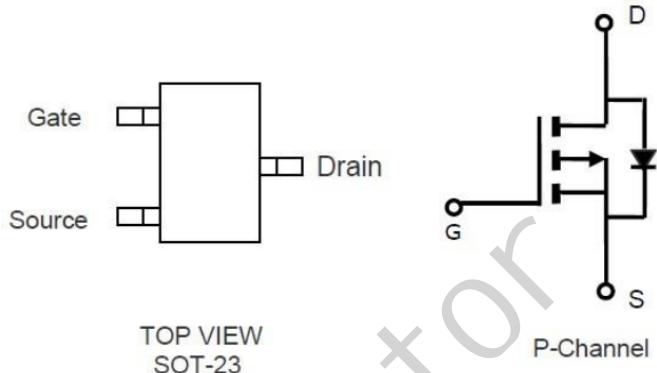


■ FEATURE

- ◆ -30V/-4.3A, $R_{DS(ON)}=44m\Omega$ (typ.) @ $V_{GS}=-10V$
- ◆ -30V/-3.5A, $R_{DS(ON)}=50m\Omega$ (typ.) @ $V_{GS}=-4.5V$
- ◆ -30V/-2.5A, $R_{DS(ON)}=65m\Omega$ (typ.) @ $V_{GS}=-2.5V$
- ◆ Super high design for extremely low $R_{DS(ON)}$
- ◆ Exceptional on-resistance and Maximum DC current capability
- ◆ Full RoHS compliance
- ◆ SOT23-3L package design



■ DESCRIPTION

The 3401 is the P-Channel logic enhancement mode power field effect transistor is produced using high cell density advanced trench technology..

This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application, and low in-line power loss are needed in a very small outline surface mount package.

■ APPLICATIONS

- ◆ Power Management
- ◆ Portable Equipment
- ◆ DC/DC Converter
- ◆ Load Switch
- ◆ DSC
- ◆ LCD Display inverter

■ ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless otherwise noted)

Symbol	Parameter	Typical	Unit
V_{DSS}	Drain-Source Voltage	-30	V
V_{GSS}	Gate-Source Voltage	± 12	V
I_D	Continuous Drain Current ($T_C=25^\circ C$)	$V_{GS}=-10V$	-4.3
	Continuous Drain Current ($T_J=70^\circ C$)		-4.0
I_{DM}	Pulsed Drain Current	-20	A
I_S	Continuous Source Current (Diode Conduction)	-1.5	A
P_D	Power Dissipation	$T_A=25^\circ C$	1.5
		$T_A=70^\circ C$	0.9
T_J	Operation Junction Temperature	150	$^\circ C$
T_{STG}	Storage Temperature Range	-55~+150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	120	$^\circ C/W$

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress rating only and functional device operation is not implied

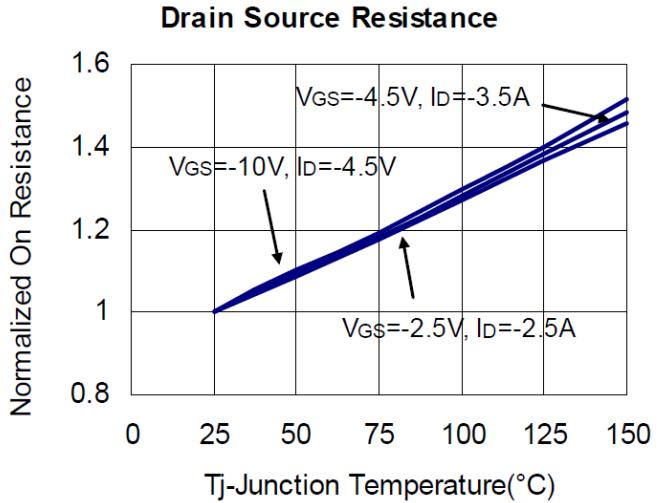
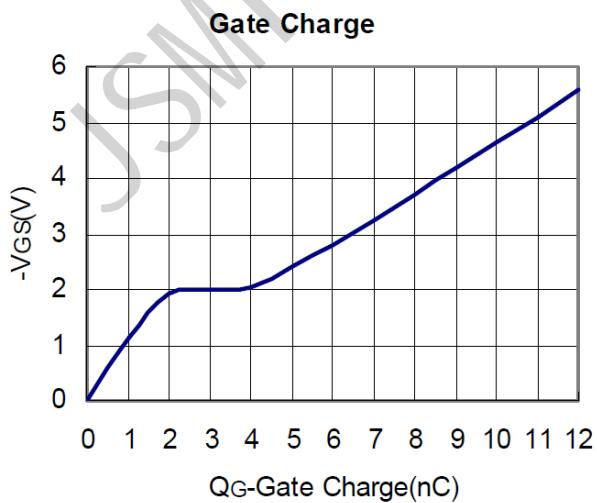
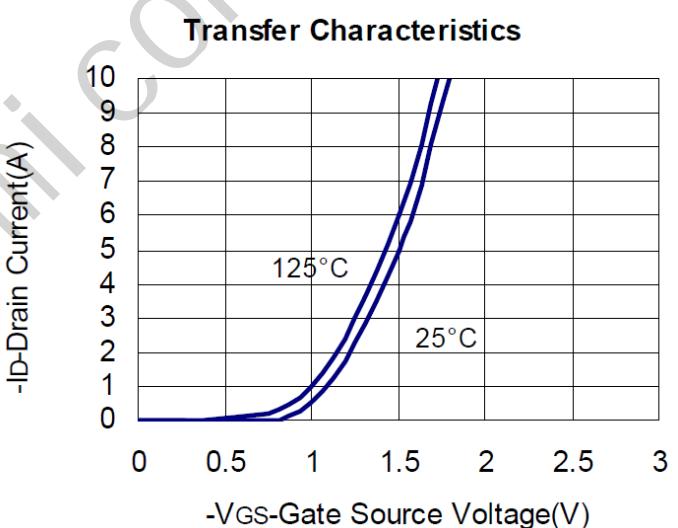
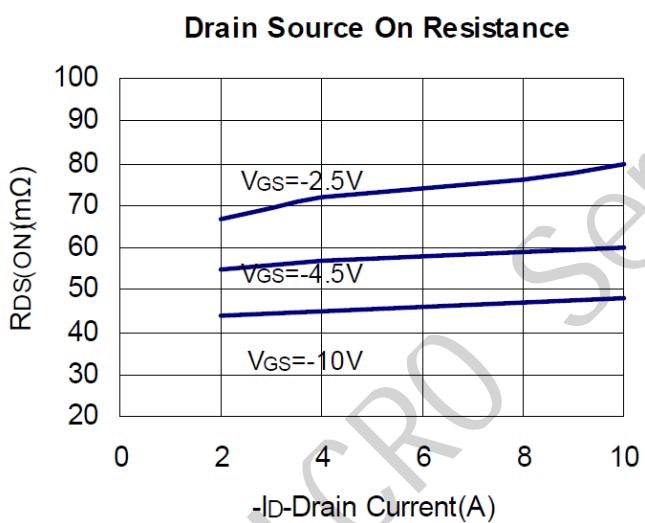
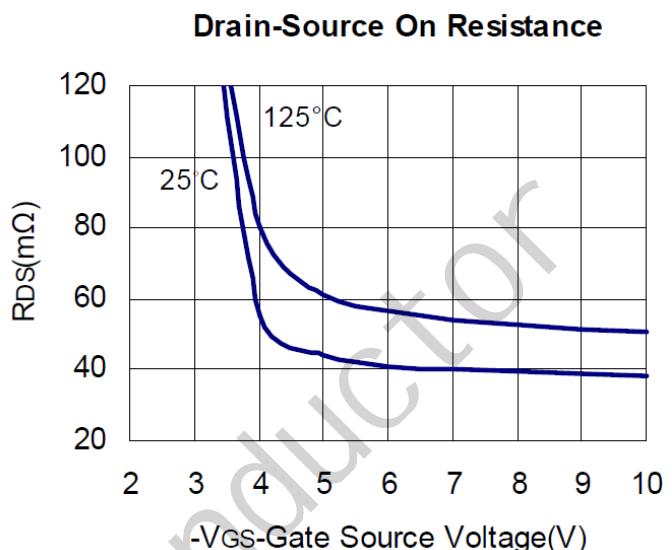
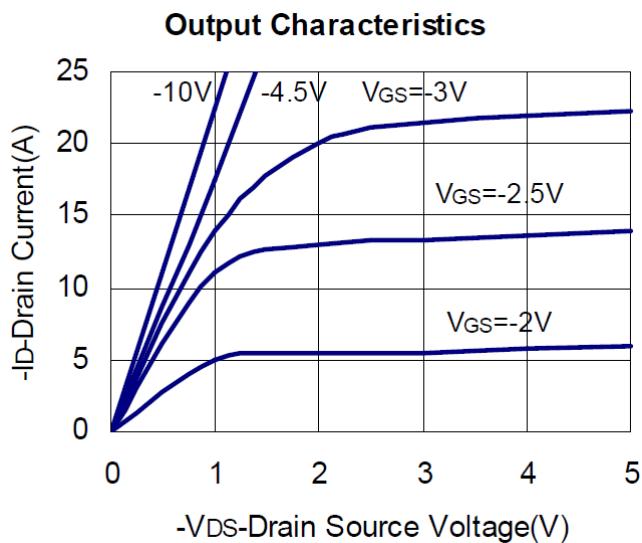
■ **ELECTRICAL CHARACTERISTICS**($T_A=25^\circ C$ Unless otherwise noted)

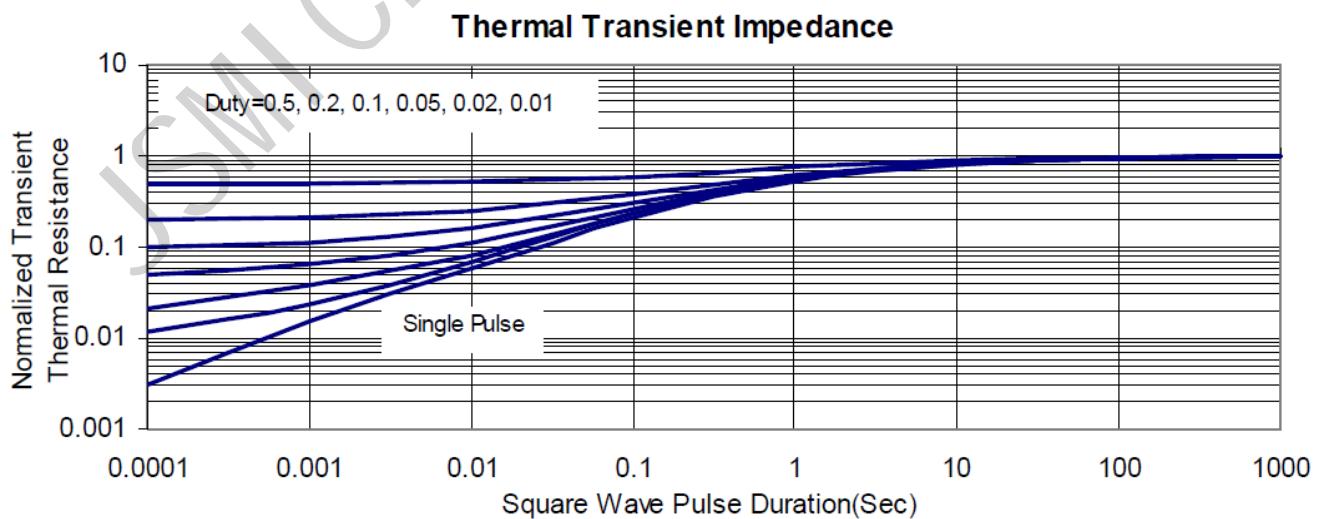
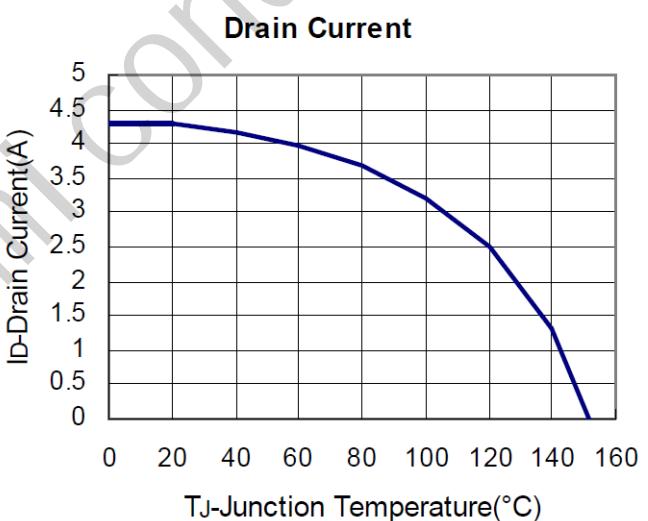
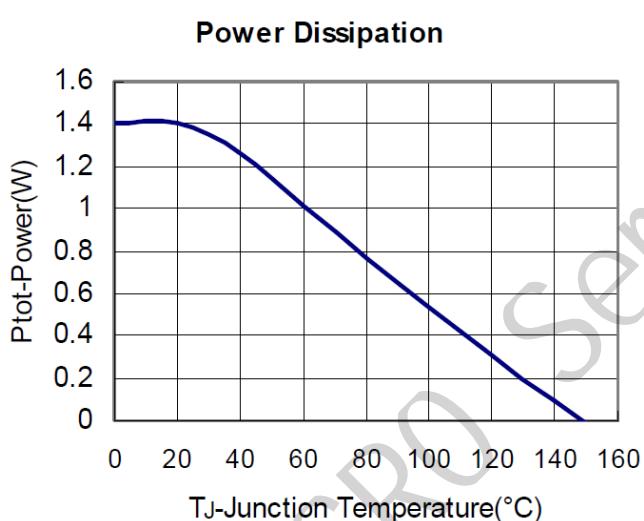
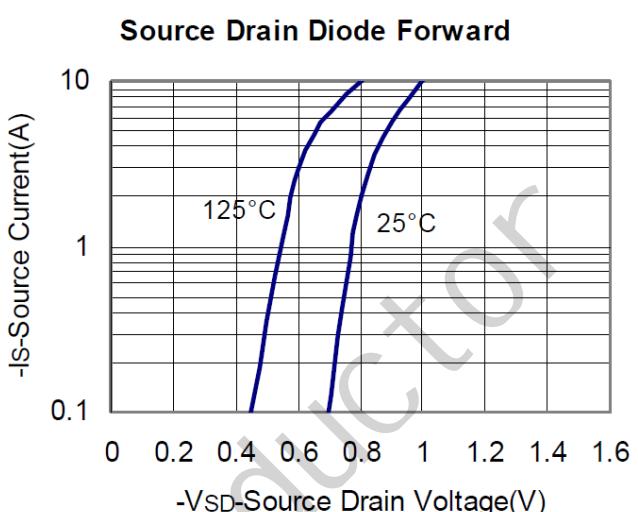
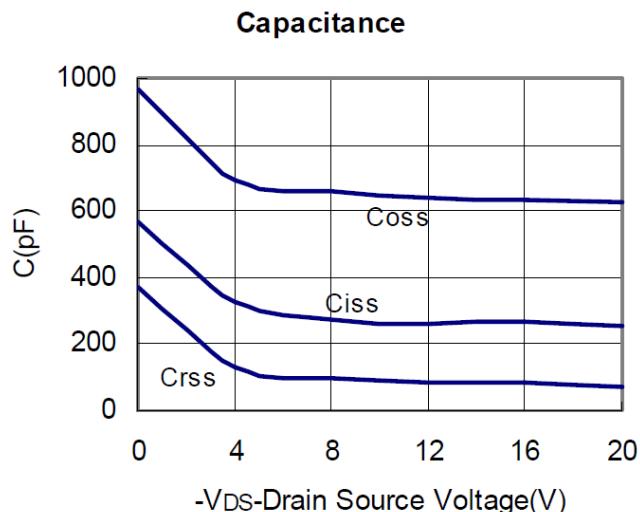
Symbol	Parameter	Condition	Min	Typ	Max	Unit	
Static Parameters							
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-30			V	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-0.6		-1.2	V	
I_{GSS}	Gate Leakage Current	$V_{DS}=0V, V_{GS}=\pm 12V$			± 100	nA	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-24V, V_{GS}=0$			-1	uA	
		$V_{DS}=-24V, V_{GS}=0$ $T_J=55^\circ C$			-5		
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS}=-10V, I_D=-4.3A$		44	52	mΩ	
		$V_{GS}=-4.5V, I_D=-3.5A$		50	58		
		$V_{GS}=-2.5V, I_D=-2.5A$		65	78		
Source-Drain Diode							
V_{SD}	Diode Forward Voltage	$I_S=-1.0A, V_{GS}=0V$		-0.7	-1.0	V	
Dynamic Parameters							
Q_g	Total Gate Charge	$V_{DS}=-20V$ $V_{GS}=-4.5V$ $I_D=-4.0A$		6.2		nC	
Q_{gs}	Gate-Source Charge			2.8			
Q_{gd}	Gate-Drain Charge			3.0			
C_{iss}	Input Capacitance	$V_{DS}=-12V$ $V_{GS}=0V$ $f=1MHz$		672		pF	
C_{oss}	Output Capacitance			280			
C_{rss}	Reverse Transfer Capacitance			102			
$T_{d(on)}$	Turn-On Time	$V_{DS}=-12V$ $I_D=-4A$ $V_{GEN}=-10V$ $R_G=3.3\Omega$		9		nS	
T_r				15			
$T_{d(off)}$	Turn-Off Time			23			
T_f				21			

Note: 1. Pulse test: pulse width<=300uS, duty cycle<=2%

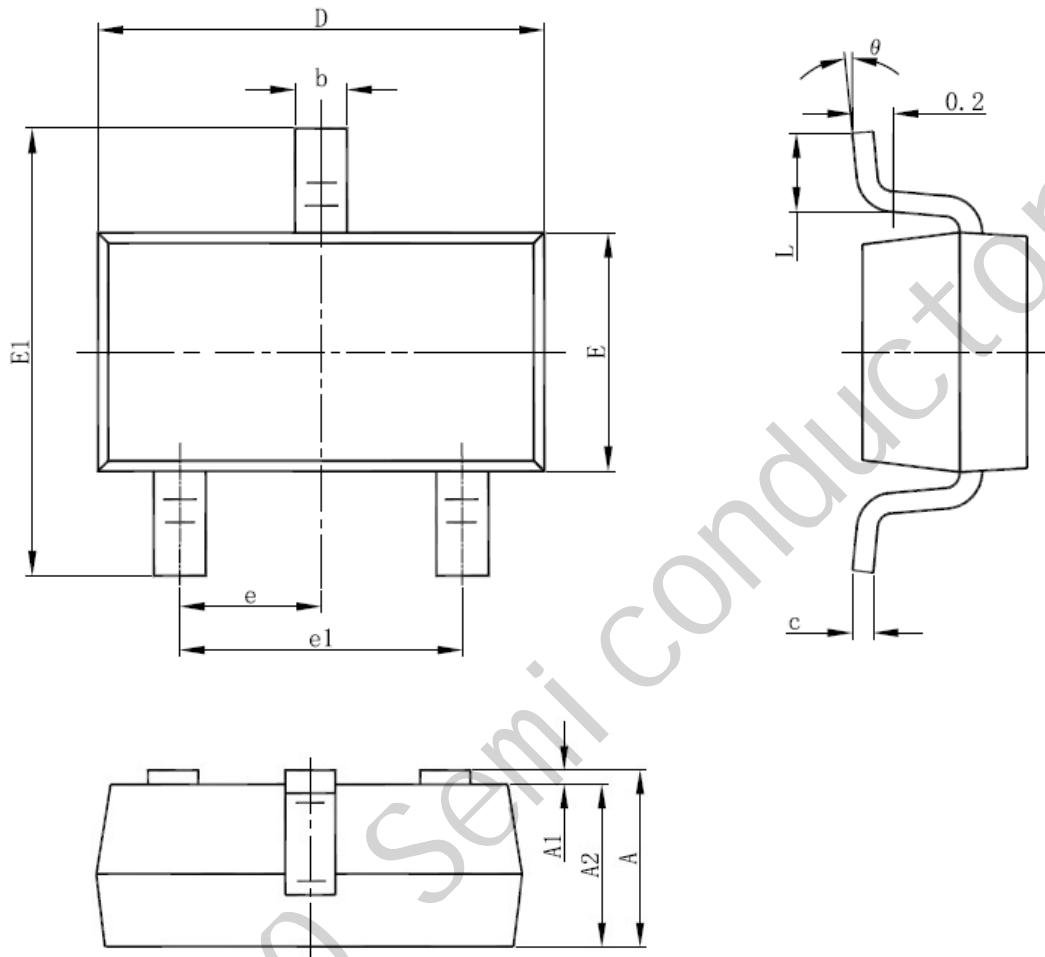
2. Static parameters are based on package level with recommended wire bonding

■ **TYPICAL CHARACTERISTICS (25 °C Unless Note)**



■ **TYPICAL CHARACTERISTICS (continuous)**


■ SOT23-3L PACKAGE OUTLINE DIMENSIONS



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
c	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E	1.500	1.700	0.059	0.067
E1	2.650	2.950	0.104	0.116
e	0.950(BSC)		0.037(BSC)	
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°